## A wide energy-window view on the density of states and hole mobility in poly (p-phenylene vinylene)

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U sing an electrochem ically gated transistor, we achieved controlled and reversible doping of poly (p-phenylene vinylene) in a large concentration range. Our data open a wide energy-window view on the density of states (DOS) and show, for the rst time, that the core of the DOS function is G aussian, while the low-energy tail has a more com plex structure. The hole m obility increases by more than four orders of magnitude when the electrochem ical potential is scanned through the DOS.

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Charge transport in disordered conjugated polymers like poly (p-phenylene vinylene) (or PPV), polypyrrole and polythiophene) [1], and disordered systems in general [2, 3, 4, 5, 6] usually proceeds via therm ally activated hopping allowing the charge carriers to move from one site to the next. In this process the energy-dependent density of states (DOS) and the charge mobility () (or the di usion constant (D)) are two key param eters. The energy distribution of the DOS is often assumed to be Gaussian [3, 7, 8] [for dipolar interaction [9] the width will be proportional to the strength of the dipoles [2, 4, 10]] or exponential [11] and both shapes have been applied with success to explain transport properties under di erent conditions [12, 13, 14, 15]. In devices such as polymeric light em itting diodes (LED s), where the carrier concentration is low, only the tail of the DOS is directly involved in the charge in jection. In eld e ect transistors (FETs) the carrier concentration c is orders of m agnitude larger and the DOS further tow ards the center of the level distribution is important. These examples show that, for a proper understanding of the electronic properties of such materials, a direct experimental determination of the shape of the DOS function over a large range of energy (or charge concentration) is essential. Until now, only a few m easurem ents have been reported.

One attempt to determ ine the DOS (from now on only valence-states are considered) in  $OC_1C_{10}$ -PPV, the workhorse in light em itting diodes, has used the tem – perature and concentration dependence of the hopping conductivity with FeC  $l_{e}$  as a dopant [16]. In another approach it is assumed that the DOS is G aussian shaped. It then follows  $\beta$ , 8, 9, 17, 18] that the carrier mobility

depends on tem perature via ln /  $(_d=k_BT)^2$ . From the experim ental determ ination of the mobility as a function of tem perature the width  $_d$  of the distribution was determ ined [17, 18] [for a discussion of som e of the sim – plifying assumptions see 8, 19]. Recently, concentration dependent DOS and data were obtained in a FET and a LED con guration [18]. All of the above mentioned experiments showed the mobility to be strongly concentration dependent. In the charge carrier concentration range covered by chemical doping with FeC L the DOS increased linearly with c [16], while for the analysis of the FET and LED experiments [17, 18] an exponential and G aussian DOS were assumed, respectively. It can be concluded that there is still no consensus on the DOS of PPV in a broad energy range.

This letter reports on the DOS and conductivity of thin spin-coated PPV lm s in a wide, well de ned energy range. The data are obtained using an Electrochem ically G ated Transistor (EGT), which was recently developed [20, 21, 22]. U sing the impressive energy range of the EGT, we are able to con m the previous data and to show for the st time that the core of the DOS function is Gaussian, while the ank has an exponential energy dependence. The low energy tailhas a more com plex structure. Conductance measurements were performed over a wide carrier concentration range and show that the hole mobility is strongly energy dependent, as also seen in results obtained with a classical FET [18]. The maximum value of the mobility exceeds previously reported values by a factor of 40. The mobility is found to vary over more than 4 orders of magnitude when the Ferm i-level is scanned over less than half an eV. In addition, our m easurem ents allow an energy calibration of the DOS and the mobility.

The electrochem ically gated transistor o ers a unique possibility of studying the transport properties of polym ers as a function of doping in a reversible way. The operating principle is based on changing the electrochem – ical potential  $\sim_{e}$  of the sam ple (OC<sub>1</sub>C<sub>10</sub>-PPV) with respect to a Ag pseudo-reference electrode (RE) by m eans of a potentiostat, see Fig. 1. The PPV layer is in electrochem ical equilibrium with the Au source-drain electrodes. Any change in potential with respect to the Ag electrode is followed by charge transfer from the Au electrodes to the PPV or vice versa and current ow to the Pt counter electrode (CE). When the potential is increased holes are injected into the PPV [23]. The hole charge is counterbalanced by anions (CD<sub>4</sub> or PF<sub>6</sub>) from the electrolyte solution (0.1 M TBAP (tetrabutylam monium perchlorate), TBAPF<sub>6</sub> (tetrabutylam monium hexa uorophosphate) or LiCD<sub>4</sub> in acetonitrile) [24] which perm eates the PPV. The number of holes stored in the PPV

In is determined by monitoring the di erential capacitance. In portant advantages of electrochem ical gating over the conventional eld-e ect transistor are the uniform charging [22] of the PPV In together with a wider doping range. At a given doping level the conductance is measured with a very small source-drain bias (10m V,  $I_{SD}$  /  $V_{SD}$  ) supplied by a Keithley 2400 source meter. Another advantage of the EGT is that the electrochem ical potential can be correlated with the vacuum level. To achieve this the potential of the Ag pseudo-reference electrode wasm easured with respect to the electrochem icalpotential of the ferrocenium / ferrocene redox reaction (0.68 V). From the literature value of the latter [25] with respect to vacuum (5.14 V), the Agpseudo-reference electrode was calculated to be at 4.47 V below the vacuum level.

The PPV samples with a typical thickness T of 180 nm were spin-coated on glass substrates with Au electrodes separated by a gap L of 1.25 up to 10 m and with an electrodes). The electrochem ical potential was controlled with a Princeton Applied Research Potentiostat/G alvanostat 273A and all experiments were carried out under Ar atm osphere. The volume  $V_P$  of the various polymer Im s was between 0.03 mm<sup>3</sup> to 0.1 mm<sup>3</sup> (accuracy 5%). From the speci c weight of the PPV one

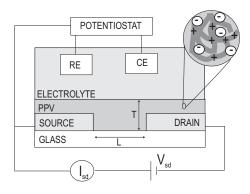


FIG.1: Schem atic picture of the electrochem ically gated transistor or EGT. The sample (PPV) is placed in an electrolyte solution. The electrochem ical potential of the sample is controlled with respect to a reference electrode (RE) using a potentiostat. The conductivity was measured by applying a sm all dc bias between source and drain. The enlargement shows schem atically how the holes on the polymer chain are compensated by the anions in the lm.

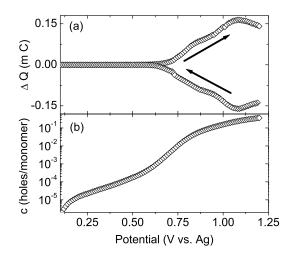


FIG.2: Electrochem ical injection of holes into the PPV lm. (a) The di erential charge Q ( $\sim_{e}$ ) stored in PPV when successive 10 mV steps are applied. The potential is de ned with respect to the A g pseudo-reference. The arrows show the two scanning directions: doping and dedoping while changing  $\sim_{e}$ . (b) D oping per monom er c( $\sim_{e}$ ) calculated from the data in (a). The reversible doping range extends over 4 orders of m agnitude.

can determ ine the density N of PPV m onom ers [26]. The density of states  $g(\sim_e)$ , was obtained from the charge Q stored in the PPV Im per  $\approx 10 \text{ meV}$  increase of  $\sim_e$ , i.e.

$$g(\gamma_e) = \frac{Q}{e \gamma_e N V_P}$$
(1)

with e the elementary charge (see Fig. 2a). The DOS is therefore determ ined directly; no assumptions are required. From 0 to 0.6 eV the amount of injected charge is small. A fler this point a strong increase is observed. At around 0.8 eV a shoulder is visible and above 1.1 eV,  $Q(\sim_e)$  starts to decrease. W ith decreasing  $\sim_e$  the maximum and the shoulder are well reproduced. M easurem ents on di erent sam ples, with di erent potential steps and other ions in solution gave very sim ilar results. The number of holes permonomerc ( $\sim_{e}$ ) at a given electrochem ical potential is obtained by integration of g (E):  $\int_{0}^{\infty} g(E) dE$  (see Fig. 2b). It can be seen that c(~e) = the doping level can be varied by electrochem ical gating in a controlled and reversible manner between 10  $\,^5$  and 0.4 holes per m onom er.

The density of states g(E) is plotted in Fig. 3, where the energy on the vertical axis is given with respect to the vacuum level. The values for g(E) on the horizontal axis range from 10<sup>4</sup> to 1 states/m onom er eV.At E =-5.55 0.02 eV, g has a m axim um. This shows that due to disorder and dispersion the HOMO levels are spread in energy and we are able to access the center of the distribution. The shoulder at about -5.3 eV reveals som e

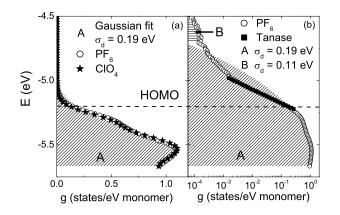


FIG. 3: The E dependence of the experimentally determined DOS (g(E)) where E is with respect to the vacuum level. The horizontal dashed line marks the HOMO (Highest Occupied Molecular Orbital) position found from cyclic voltammetry [27, 28]. (a) E vs. g(E) using PF<sub>6</sub> and ClO<sub>4</sub> as anions. A Gaussian function with = 0.19 eV (area A) to the data well. (b) E vs. g(E) for PF<sub>6</sub> on a linear-log. scale. Below g = 0:1 states=(eV monomer) deviations from the Gaussian t are visible. The lled squares are the PPV FET -data by Tanase et al. [18], which are well described by an exponential function. At the lowest values of g(E) additional structure appears, which in a limited energy range would allow a description with a Gaussian with a width of 0.11 eV (area B) as used for PPV LED s by Martens et al. [9] and Tanase et al. [18]

additional structure in the measured DOS.By tting the data to a Gaussian distribution

$$g(E) = \frac{N_{m}}{2} \exp[((\frac{E_{m} E_{ct}}{2})^{2}];$$
(2)

nd a width  $_d = 0.19$ 0:01 eV , centered at E  $_{\rm ct}$  = we 5:55 0:02 eV (diagonally shaded area<sub>R</sub>A in Fig. 3). The number of states permonom  $erN_m = q(E) dE$  has a value of 0:52 0:01 when we integrate over the whole Gaussian [29]. The measured DOS validates the assum ption of a Gaussian distribution [3] in the core (g > 10<sup>1</sup> states=(eV m onom er)). For g between 10  $^3$  and 10  $^1$ states= (eV m onom er) the data follow an exponential dependence, see the logarithm ic-linear plot of Fig. 3b. The DOS in this range measured by Tanase et al. in a solid state FET con guration [18] (solid squares in Fig. 3b) is in very good agreem ent with our data.

In general ions in the dielectric will in uence the energy landscape and broaden the DOS [14]. The data presented here compare well with those of Tanase et al. [18], where no ions are present in the lm. Hence, the intrinsic level distribution of the investigated  $OC_1C_{10}$ -PPV must be su ciently broad, such that an extra contribution by the ions is not observable in our experiments. There is no guarantee that this also holds for the data at higher doping; the intrinsic width of PPV might therefore be lower than 0.19 eV. At very low doping the inuence of the ions is expected to be small. Here, around

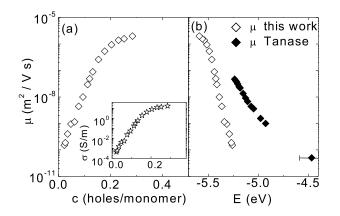


FIG. 4: (a)The hole mobility () calculated from the conductivity ( - the inset) as function of doping. Because the measurements had to be performed in a two-point contact con guration, the attening of at high c might be caused by contact resistances. Hence, actual values of or might be even higher. (b) The dependence of hole mobility on energy or electrochemical potential  $\gamma_{\rm e}$ . At lower doping, corresponding to energies E > -5.2 eV, we have included (closed symbols) determined in a solid-state FET and LED by Tanase et al. [18]. The deviations are discussed in the text. Both plots are on a logarithm ic-linear scale.

g 10 <sup>4</sup> states= (eV m onom er), the data allow for tting to a Gaussian with  $_d = 0.11$  eV (horizontally shaded area B in Fig. 3b), as reported in Refs. 17 and 18. Note, see Fig. 3b, that the Gaussian distribution in this doping regime is a taile ect, which is not representative for the m ain distribution.

On inspection of the DOS it is clear that the assignment of the HOMO level at -5.2 eV [27, 28] (horizontal dashed line in Fig 3), as determined by cyclic voltam – metry (location at 10% of the peak value), is relatively arbitrary. The value of -5.2 eV corresponds to the point at which a strong increase in DOS is observed. How – ever, many states are already available for values of E up to -4.5 eV. This means that in LED applications a deviation of the "HOMO level" of 0.7 eV from the cyclic voltam metric value is possible. This has to be included in quantitative descriptions of charge in jection and carrier mobility in devices [14].

W hen a small voltage di erence is applied between the source-drain contacts, the conductivity of the PPV layer can be measured as a function of doping regulated by  $\sim_{e}$ , see Fig. 4. The conductivity, which was checked to be ohm ic up to the highest eld of  $10^{\circ}$  V=m, increases by ve orders of magnitude, as the doping is increased from about 0.02 to 0.30 holes per monom er. A similar strong increase was previously reported for FeC  $l_{a}$  doped PPV [16]. The values of are calculated with a constant thickness of PPV, not taking into account e ects of swelling. Because them easurem ents had to be perform ed in a two-point contact con guration, the attening of at high c m ight be caused by contact resistances, which means that actual values of or might be even higher. From the measured conductivity the hole mobility () can be determ ined via the relation: =  $N p_t e$  with  $p_t$ the num ber of holes per m onom er participating in transport and e the elem entary charge. The states involved in hopping are those within  $k_B T$  of the chemical potential  $k_B T = 2$  g (E) dE. The results, presented  $[31], p_t(\sim)$ in Fig. 4, con m that the mobility is concentration, or better, energy dependent [16, 18]. For a doping level of 0.3 a mobility of 2 10  $^{6}$ m<sup>2</sup>/V s is obtained, more than a factor of ten higher than the highest value found by Tanase et al. [18] for comparable eld values, but at 0.02 holes per m onom er. The lower m obilities obtained in the EGT compared to the solid-state FET at the same doping levels are likely due to the presence of the anions that tend to localize the mobile holes. In addition, in the solid-state FET transport takes place primarily in the

rst PPV layers close to the interface. The higher structural order will have a favorable e ect on the mobility.

In conclusion, by using an EGT the DOS of a polymer can be determined over more than one eV or a doping range extending over four orders of m agnitude. A com parison with the DOS obtained with a solid-state FET [18] reveals that data below 0.1 states = (eV m onom er) (doping levels below 10<sup>2</sup> holes per m onom er) are representative for the intrinsic level distribution of 0 C<sub>1</sub>C<sub>10</sub>-PPV. The shape of the DOS function is com plex. W hile the core is well described by a Gaussian function (its width of 0.19 eV has to be considered an upper boundary for the intrinsic width), the ank decays exponentially and the tail at very low densities allows a description with another Gaussian. The hole mobility is found to vary from 10  $^{10}$  m  $^2$  =V s to 10  $^{6}$  m  $^2$  =V s, as the chem icalpotential changes from -5.3 eV to -5.6 eV.W e have shown that PPV can be electrochem ically doped with a high degree of control and reversibility. The accessible energy window is much larger than that of previously used methods. Thus electrochem ical gating appears to be a powerfulm ethod for studying charging and transport properties of conducting polymers.

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